

# Lifetime Reliability Trojan based on Exploring Malicious Aging

Tien-Hung Tseng and Kai-Chiang Wu

Department of Computer Science

National Chiao Tung University, Hsinchu, Taiwan

E-mail: {eric830303.cs05g@g2.nctu.edu.tw and kcw@cs.nctu.edu.tw}

**Abstract**—Device aging, which causes significant loss on circuit performance and lifetime, has been a primary factor in reliability degradation of nanoscale designs. In this paper, we propose to take advantage of aging-induced clock skews (i.e., make them useful for aging tolerance) by manipulating these time-varying skews to compensate for the performance degradation of logic networks. The goal is to assign achievable/reasonable aging-induced clock skews in a circuit, such that its overall performance degradation due to aging can be minimized, that is, the lifespan can be maximized. On average, 25% aging tolerance can be achieved with insignificant design overhead. Moreover, we also apply  $V_{th}$  assignment to further mitigate the aging-induced degradation of logic networks. Averagely, 39.74% aging tolerance can be achieved when aging manipulation and  $V_{th}$  assignment are applied.

## I. INTRODUCTION

Due to escalating complexity of hardware design and manufacturing [1], integrated circuits (ICs) are usually designed and fabricated in multiple locations worldwide. Moreover, some design tools are also supplied from different units. With the utilization of third-party IP components and off-shore IC manufacturing, the overall cost and time-to-market are significantly reduced. However, hardware security becomes more subject to various kinds of tampering in the supply chain [2][3]. Typically, a hardware system does no more than its requirements. Doing more than required, hardware Trojan horses (HTHs) can be implanted to facilitate the leakage of confidential information or cause the failure of a system [4]-[5]. Outsourcing (e.g., third-party IP components, design tools and off-shore IC manufacturing) makes malicious HTH attacks possible. In order to introduce the motivation of deploying HTH attacks, here we make some scenario from various aspects, i.e., attackers. Manufacturers: Given a design house A with its competitor B, in order to interfere B's commercial development, A paid B's ICs manufacturer M such that M tampered B's layout, making B's product(s) malfunction earlier than expected. Design-tool suppliers: Given a country C with its imaginary enemy D, and we assume that D's design houses utilize at least one design tool supplied from C's software corporation S. For the purpose of obstructing D's high-tech military weapon development, C forced S to embed malicious mechanisms in its software merchandise. Therefore, no matter what kinds of military equipment D produces, they are stealthily put HTH in the inner ICs. After the insertion of HTHs, it is difficult to prove their existence since they

are pervasive and inappreciable. In this sense, the proposed research provides new primitives for aforementioned hardware security threats, by exploring the feasibility of different HTH attacks and associated detection/prevention countermeasures. Reliability Trojan is one of the main categories of HTH attacks because its behavior is progressive and is thus not trivial to be detected, or not considered malicious. Time-dependent dielectric breakdown (TDDB), bias temperature instability (BTI), and electromigration (EM) are some of the critical failure mechanisms affecting lifetime reliability. With the continuous shrinking of transistor and interconnect dimensions, the rate of such progressive wear-out failures is getting higher. In addition, due to the increasing transistor density without proportional downscaling of supply voltage, the power density and thus the operating temperature will rise significantly, which further accelerates the failure mechanisms because they are all exponentially dependent on temperature. In this work, we propose to insert reliability Trojan into a circuit which can finely controls the circuit lifetime as specified by attackers (or even designers), based on manipulating BTI-induced aging behavior in a statistical manner.

## II. RELATED WORK

Studies about reliability Trojan have been proposed since last few years. [6] details BTI and HCI effects which induce aging failures, and accelerates the effects by aggravating the most influential parameters of BTI and HCI. [7] proposes a few Trojan designs which accelerate EM, BTI and TDDB effects by stressing/modifying specific interconnects and gates. Some studies also try to control the lifetime of a circuit by counters or timers. In [8], authors present a Trojan which controls lifetime by analog mechanism. It siphons charge from target wire and stores to a capacitor until voltage on the capacitor rises above the threshold and sets its output flip-flop to a desired value. [9] presents an unmodified Trojan by analyzing the netlist of a circuit to identify its critical paths; then they generate patterns/instructions for stressing those paths. These patterns can be fed by external programs or embedded devices to accelerate the aging and decrease the circuit performance and lifetime. [8] [9] focus on the logic blocks which highly depend on users' operational modes. However, [6] does not estimate circuit lifetime in detail and [7] has relatively high cost based on using counters to control lifetime. To predict circuit lifetime with Trojans, [10] uses

mathematical modeling to estimate circuit reliability, but it only tries on tiny circuit C17 and does not consider aging. In addition, [11] proposes an idea using aging effects to induce a circuit into its redundant states (i.e., operational modes) and thereafter execute malicious function. This paper proposes a method of hardware Trojan insertion to control the lifetime of a circuit based on manipulating the rate of circuit aging. We consider (i) the aging of both clock trees and combinational logical paths, and (ii) the correlation of aging rates between critical paths. These considerations ensure the effect of our proposed Trojan to be manifested on time under all possible workloads due to various users' operational conditions. More clearly, we present a methodology that deploys duty-cycle converters (DCCs) into a clock tree to accelerate the aging of predesignated clock buffers/inverters associated with critical paths. Those paths will fail around the time we set regardless of operational conditions.

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